# Special Issue

# Advancements in IoT and Machine Learning: Unveiling Synergies and Challenges

### Message from the Guest Editors

This Special Issue aims to foster interdisciplinary discussions and collaborations among researchers, practitioners, and industry experts in the domains of IoT and Machine Learning. By compiling diverse perspectives and cutting-edge research, we strive to pave the way for innovative solutions and applications that harness the full potential of IoT and ML technologies. We look forward to receiving your contributions and advancing the state of the art in this exciting field. This Special Issue welcomes original research contributions, review articles, and case studies that address, but are not limited to, the following topics: IoT-enabled Intelligent Systems Machine Learning Techniques for IoT Security and Privacy Challenges Scalability and Resource Constraints Applications and Case Studies

### Guest Editors

Prof. Dr. Hani Hamdan

Dr. Jinan Charafeddine

Prof. Dr. Bang Wang

### Deadline for manuscript submissions

closed (31 October 2024)

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# About the Journal

### Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

### Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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